Contribution ID: 25 Type: not specified

## **Extraction of physical quantities from edge-TCT** measurements

Tuesday 22 November 2011 09:20 (20 minutes)

A method to extract trapping times from edge-TCT measurements is proposed. It is based on extraction of point charge drift velocity profile with corresponding electric field and determination of transfer function of the electronics used in edge-TCT measurements. The method is currently under the development however some preliminary results will be presented in this talk.

Primary authors: DOLENC KITTELMANN, Irena (CERN); MOLL, Michael (CERN); PACIFICO, Nicola

(CERN)

Presenter: DOLENC KITTELMANN, Irena (CERN)

Session Classification: Detector characterisation